

positive comments from teachers and students, presenters who feel that they reached the students, and administrators from industry and education who want to continue the program.

Students need a reason to learn. Schools need to see what a valuable resource their local technical community can be. Industry needs to see how easy it is to help. And to the little girl who wrote "I am glad jat you got to be her"—I am glad I got to be there too!

CATHERINE WAGNER

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Catherine Wagner holds a degree in Education and is the Precollege Education Coordinator for the Engineering Technology Division (ETD) at Oak Ridge National Laboratory. Technology in Education: A Guidebook for De-

veloping a Science and Math Education Support Program, ORNL TM-12145, details ETD's education program and serves as an easy-to-use guide for any technical organization or school that would like to develop an individualized science and math education support program. Limited copies are available by writing to Catherine Wagner, Oak Ridge National Laboratory, Building 9102-1/MS 8038, P. O. Box 2009, Oak Ridge, Tennessee 37831-8038. □

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